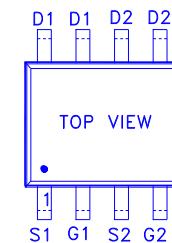
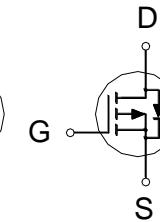
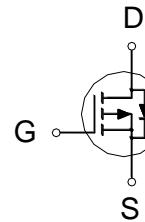


NIKO-SEM
**Dual P-Channel Enhancement Mode
Field Effect Transistor**
P2003KV
SOP-8
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-30V	22mΩ	-8A


G : GATE
D : DRAIN
S : SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 25	V
Continuous Drain Current $T_A = 25^\circ\text{C}$	I_D	-8	A
$T_A = 70^\circ\text{C}$	I_D	-6	
Pulsed Drain Current ¹	I_{DM}	-40	
Avalanche Current	I_{AS}	-30	
Avalanche Energy	E_{AS}	45	mJ
Power Dissipation $T_A = 25^\circ\text{C}$	P_D	2	W
$T_A = 70^\circ\text{C}$	P_D	1.28	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W

¹Pulse width limited by maximum junction temperature.**ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-1	-1.5	-3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 25V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -24V, V_{GS} = 0V$			-1	μA
		$V_{DS} = -20V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			-10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = -4.5V, I_D = -7A$		29	34	$\text{m}\Omega$
		$V_{GS} = -10V, I_D = -9A$		20	22	
Forward Transconductance ¹	g_{fs}	$V_{DS} = -5V, I_D = -9A$		20		S

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DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = -15V, f = 1MHz$	1480			pF
Output Capacitance	C_{oss}		334			
Reverse Transfer Capacitance	C_{rss}		231			
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	2.9			Ω
Total Gate Charge ²	Q_g	$V_{GS} = -10V$	30			nC
		$V_{GS} = -4.5V$	15			
	Gate-Source Charge ²		5			
	Gate-Drain Charge ²		6			
	Turn-On Delay Time ²		13			
	Rise Time ²		8			
Turn-Off Delay Time ²		$I_D \approx -9A, V_{GS} = -10V, R_{GS} = 6\Omega$	16			nS
Fall Time ²			12			
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_A = 25^\circ C$)						
Continuous Current	I_S				-2	A
Forward Voltage ¹	V_{SD}	$I_F = -9A, V_{GS} = 0V$			-1	V
Reverse Recovery Time	t_{rr}	$I_F = -9A, dI/dt = 100A/\mu s$	40			nS
Reverse Recovery Charge	Q_{rr}		26			nC

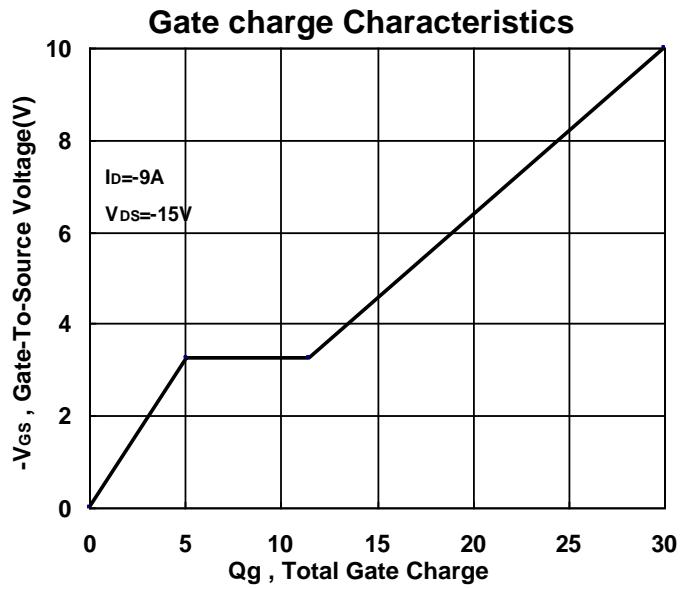
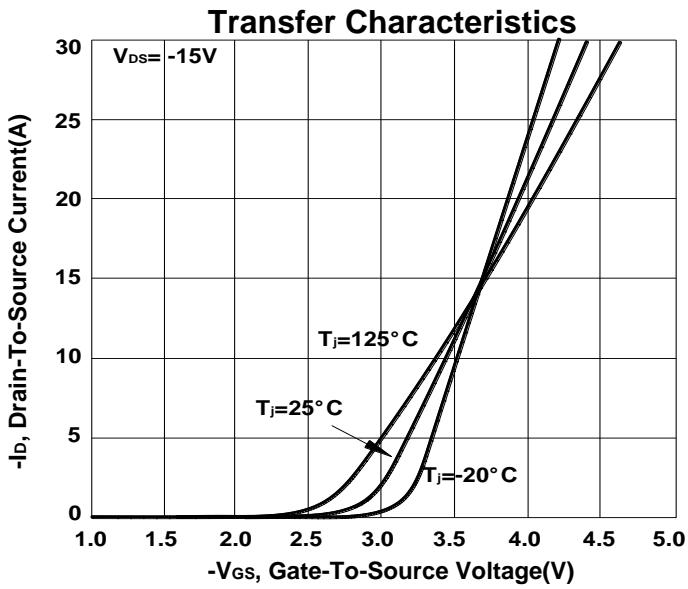
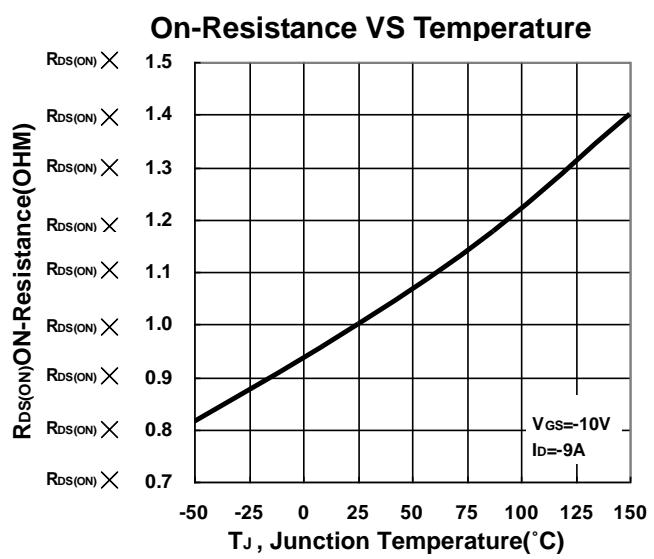
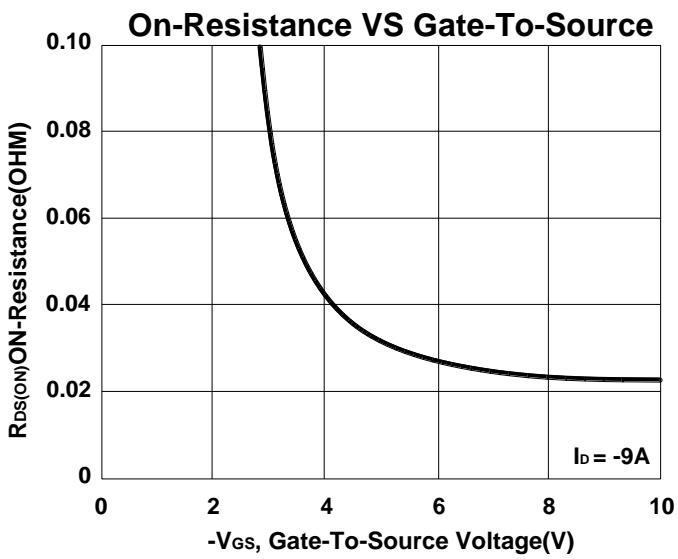
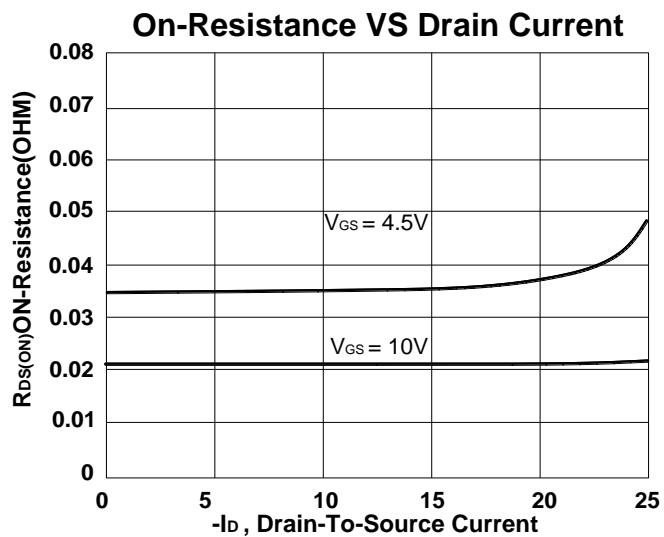
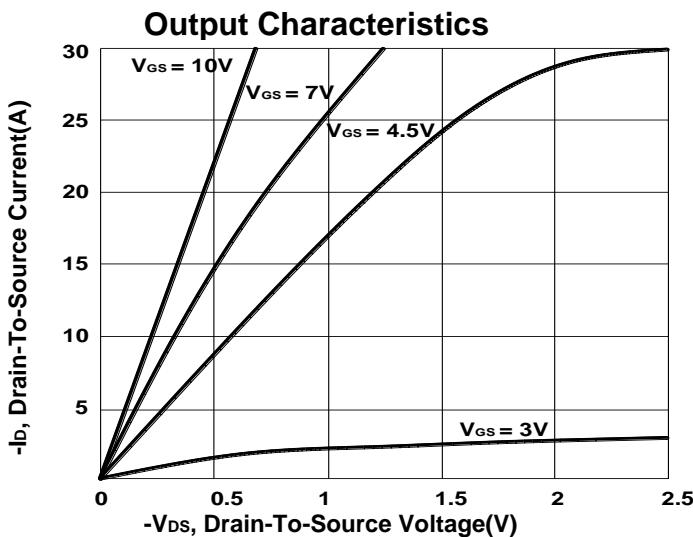
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

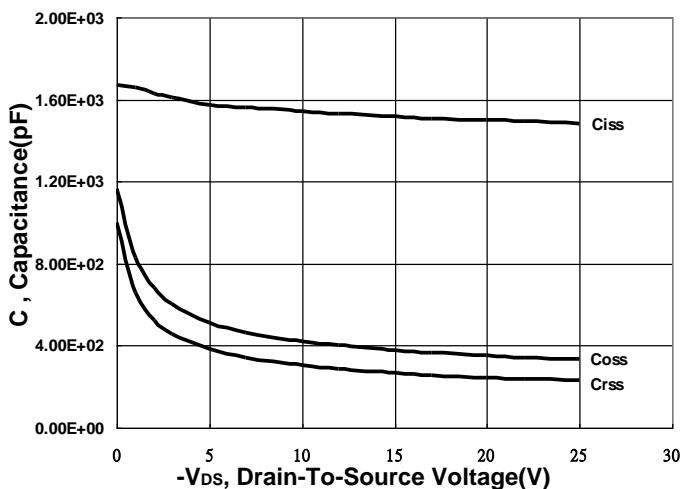
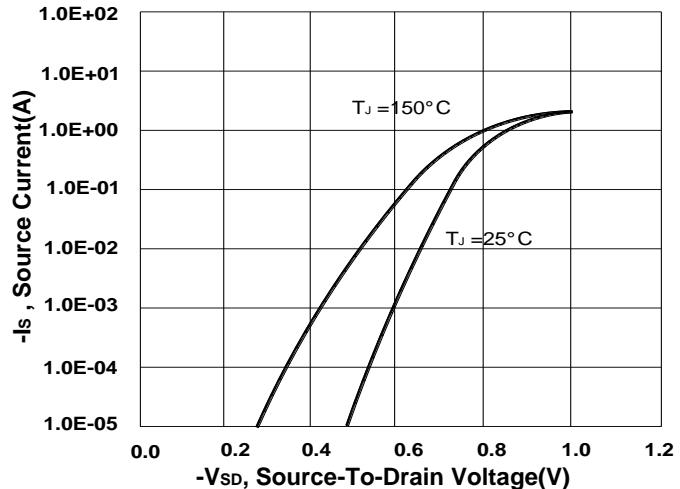
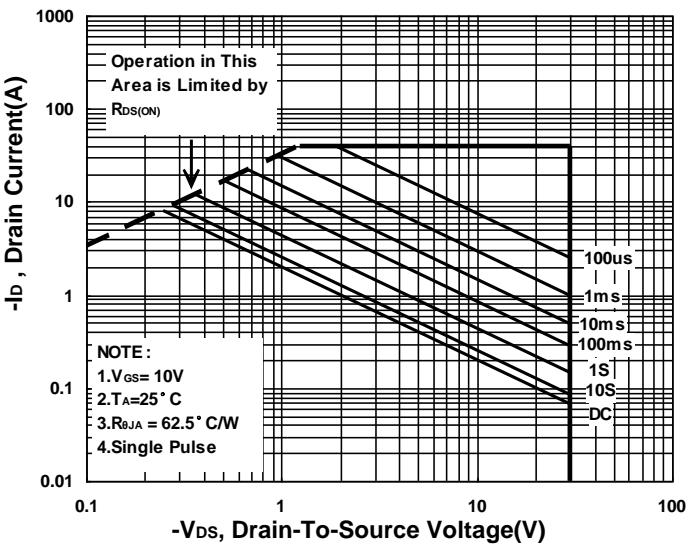
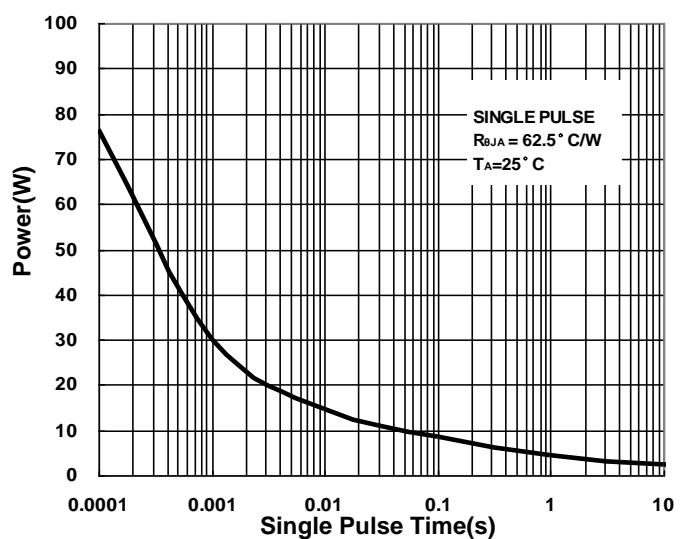
REMARK: THE PRODUCT MARKED WITH "P2003KV", DATE CODE or LOT #

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NIKO-SEM**Dual P-Channel Enhancement Mode
Field Effect Transistor****P2003KV
SOP-8
Halogen-Free & Lead-Free****Capacitance Characteristic****Body Diode Forward Voltage VS Source current****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**